# Lecture 08 Analog Input

## CE346 – Microprocessor System Design Branden Ghena – Fall 2021

Some slides borrowed from: Josiah Hester (Northwestern), Prabal Dutta (UC Berkeley)

Northwestern

#### Administrivia

• Project proposal feedback late this weekend

• Various grades will be released soon

• Lab hours today 5-6:30pm

• Remember to answer the post-lab questions on Canvas

#### Today's Goals

- Explore methods for sensing analog signals
  - Comparators
  - Analog-to-Digital Converters
- Discuss nRF implementation of these peripherals

#### Outline

#### Comparators (and nRF implementations)

• General ADC Design

• nRF ADC Implementation

#### Analog signals

- Exist in infinite states
  - From a maximum to a minimum
- Often used for interactions with the real world
  - Sensors usually generate analog signals
- Microbit example: microphone



#### Interacting with analog signals

Microcontrollers are inherently digital

• Need a method for translating analog signal into a digital one

- Options:
  - 1. Determine if signal is higher or lower than some amount (Boolean)
  - 2. Determine voltage value of signal (N-bit number)

#### Interacting with analog signals

Microcontrollers are inherently digital

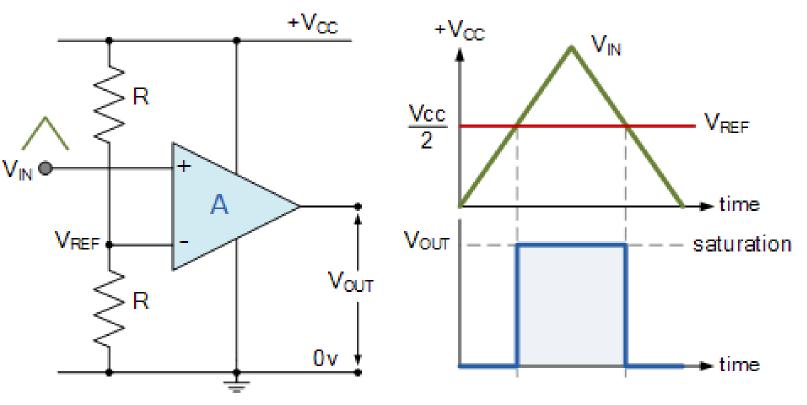
• Need a method for translating analog signal into a digital one

- Options:
  - 1. Determine if signal is higher or lower than some amount (Boolean)
  - 2. Determine voltage value of signal (N-bit number)

#### **Determination is done by a Comparator**

General comparator design

- Compares an analog input signal to a reference voltage
- V<sub>OUT</sub> digital signal
   High: V<sub>IN</sub> > V<sub>REF</sub>
   Low: V<sub>IN</sub> < V<sub>REF</sub>
- Advantages:
  - Simple
  - Low power

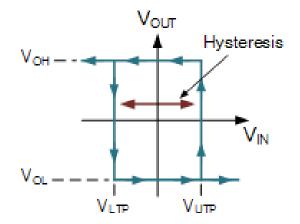


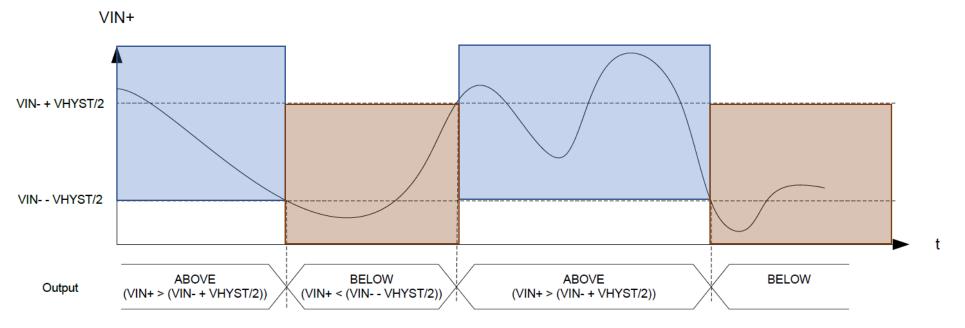
#### Comparator design questions

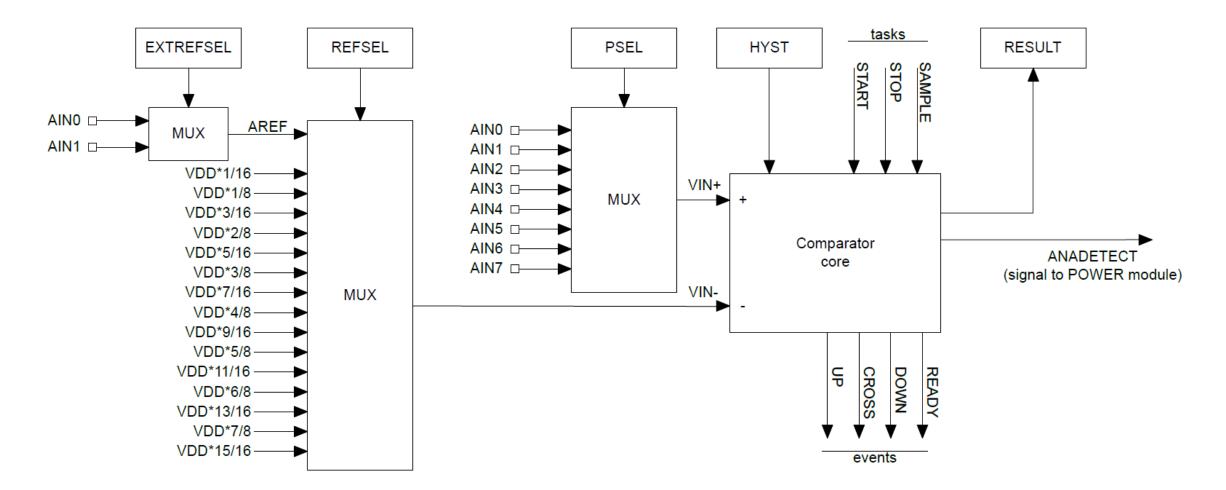
- What reference voltages are available?
  - A few internal voltages
  - Usually also allows external references from input pins
- When is an output generated?
  - Usually when status changes
    - Low-to-high, High-to-low, Both (like GPIO interrupts)

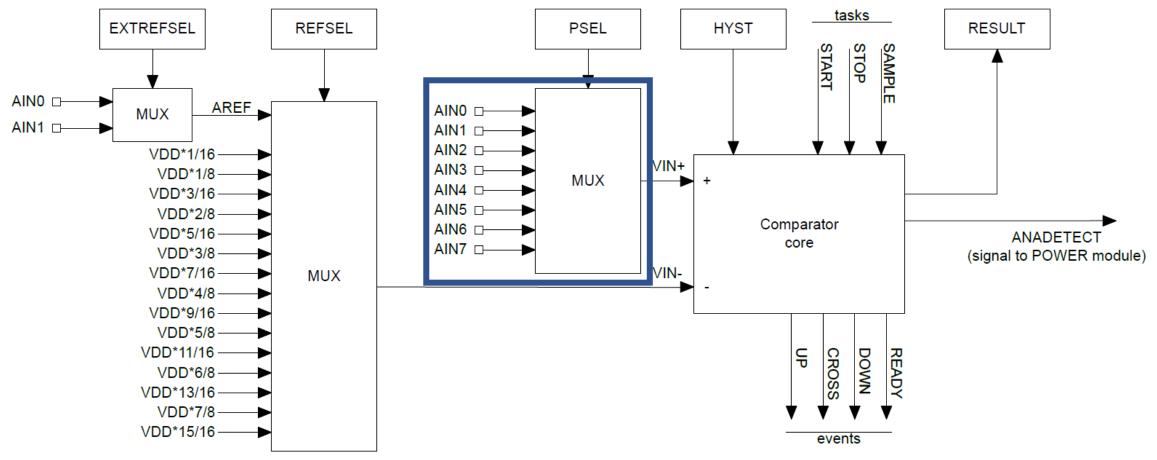
#### Hysteresis

 A window added around signal state changes to prevent small amounts of noise from changing the output

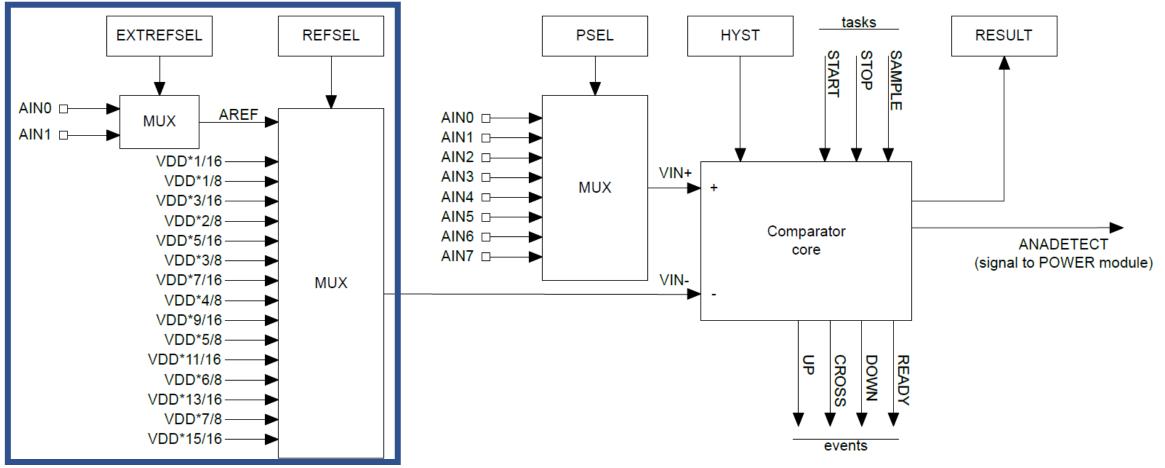




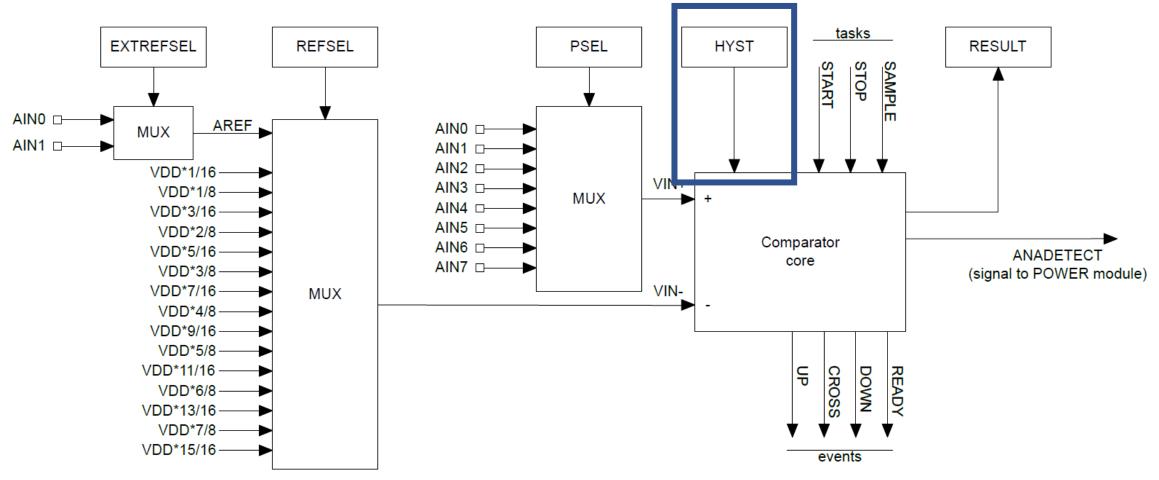




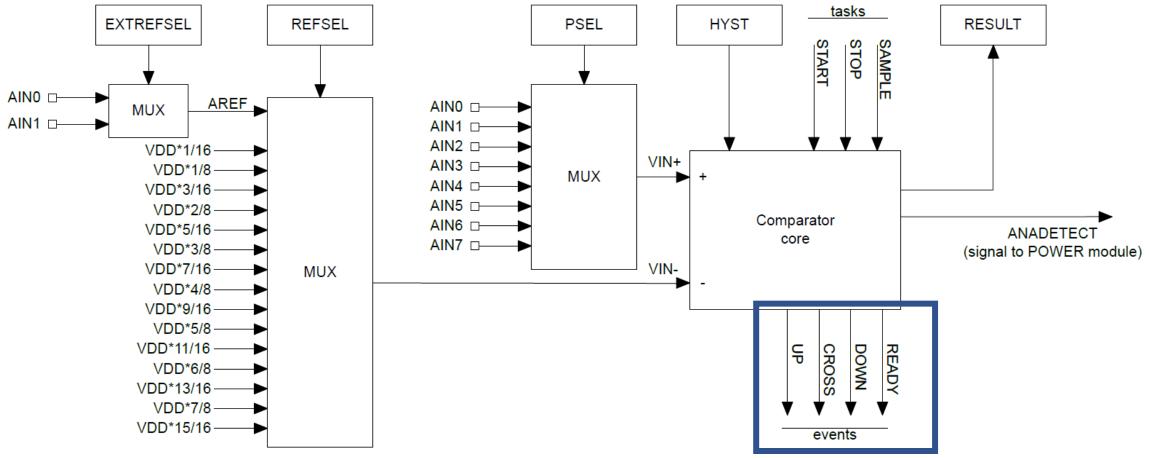
• Input: one of eight analog input pins



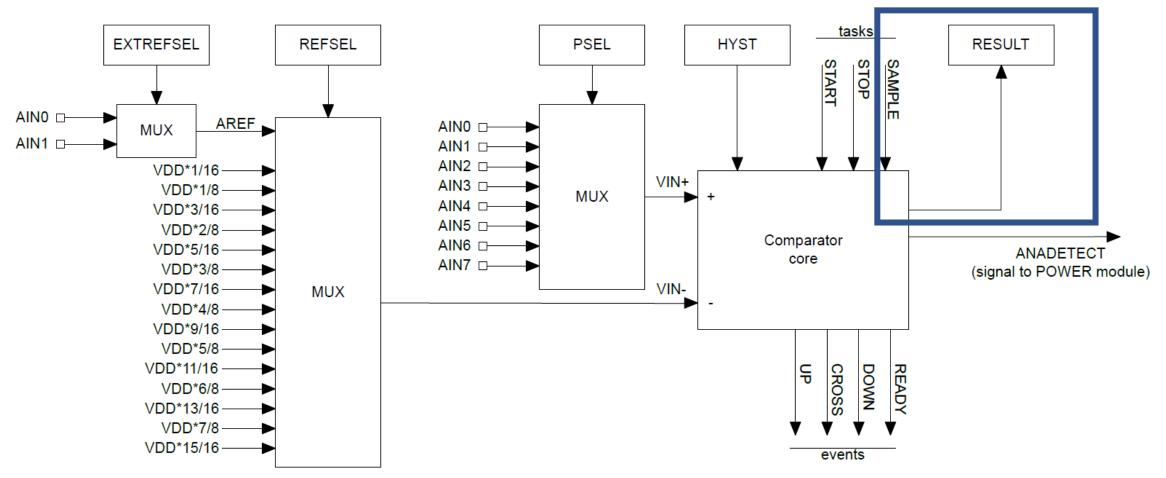
• Reference: one of two analog inputs or selection of VDD \* N/16



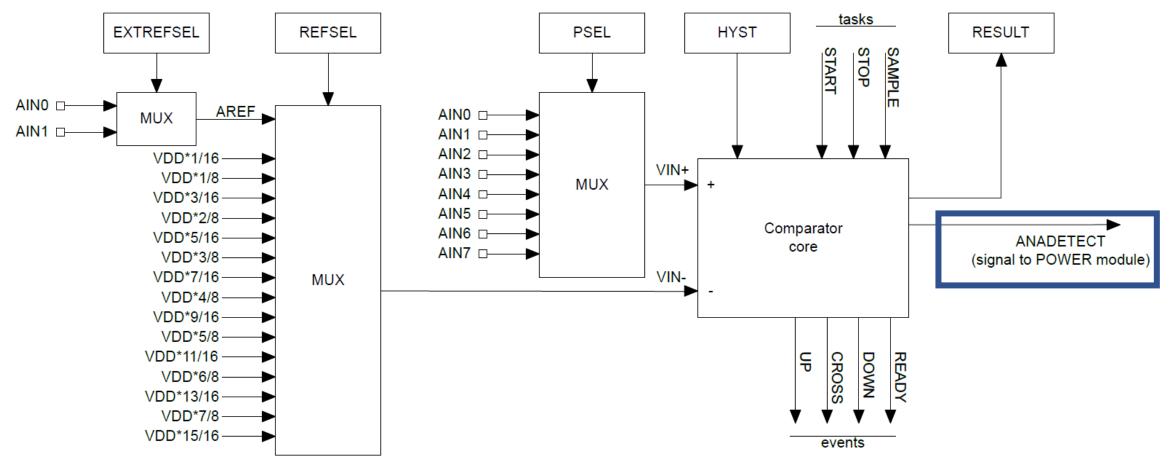
• Hysteresis: +/- 50 mV range around VIN- when enabled



• Events: transition signals + ready ( $\sim$ 150 µs)

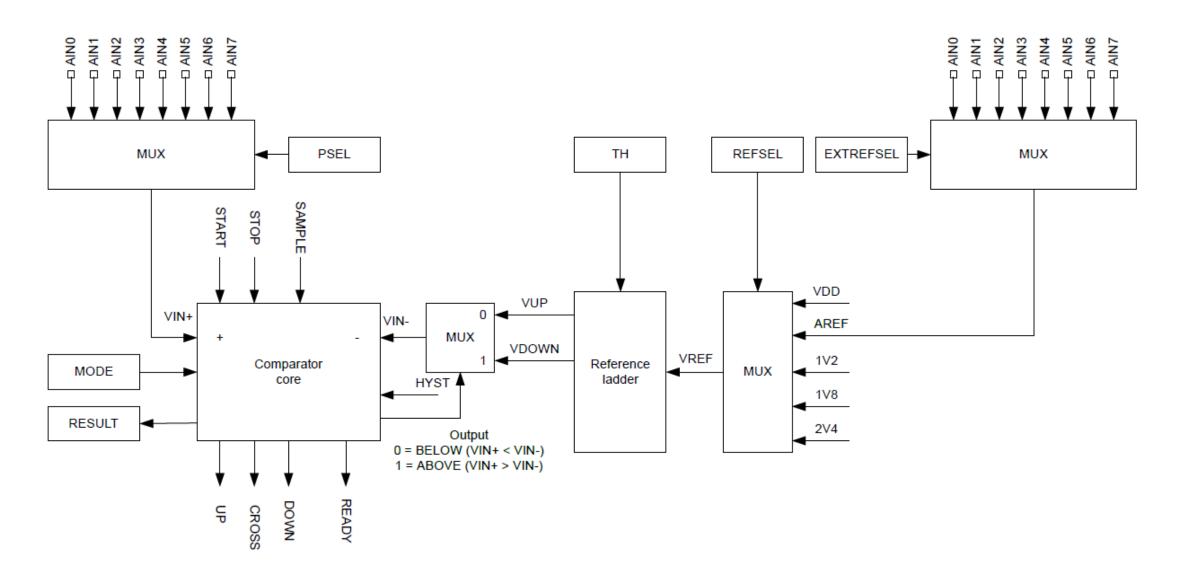


• Can also request what the current comparison state is (high/low)



• Can be used for low-power wakeup of microcontroller

#### nRF COMP peripheral



#### nRF COMP peripheral

- Analog Comparator (not low power)
  - More advanced version of a comparator (otherwise similar)
- What advantages would a more capable comparator have?
  - Configurable hysteresis
    - LPCOMP: +/- 50 mV COMP: any of the N/64 voltage levels
  - Faster detection
    - LPCOMP: 5  $\mu$ s COMP: 0.1-0.6  $\mu$ s (depending on power mode)
  - More possible reference voltages
    - LPCOMP: VDD or input COMP: VDD, 1.2v, 1.8v, 2.4v, or input
    - LPCOMP: 16 levels COMP: 64 levels

Break + Question: Internal reference voltages

Why have internal voltage references other than VDD?

Break + Question: Internal reference voltages

#### • Why have internal voltage references other than VDD?

- What if want you want to measure *is* VDD?
  - Battery voltage
  - Did someone just unplug me?
  - etc.
- What if VDD isn't stable?
  - Battery voltage
  - Energy-harvesting system
  - Hard to know what any particular value means...

#### Outline

• Comparators (and nRF implementations)

General ADC Design

• nRF ADC Implementation

#### Interacting with analog signals

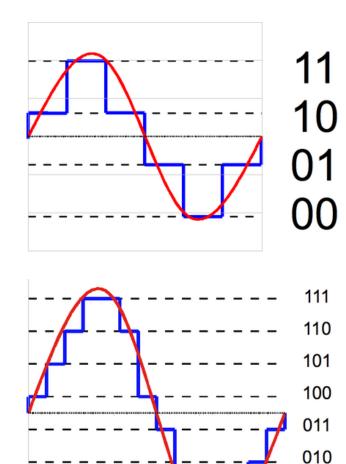
Microcontrollers are inherently digital

• Need a method for translating analog signal into a digital one

- Options:
  - 1. Determine if signal is higher or lower than some amount (Boolean)
  - 2. Determine voltage value of signal (N-bit number)

Translation is done by an Analog-to-Digital Converter (ADC)

#### Quantization

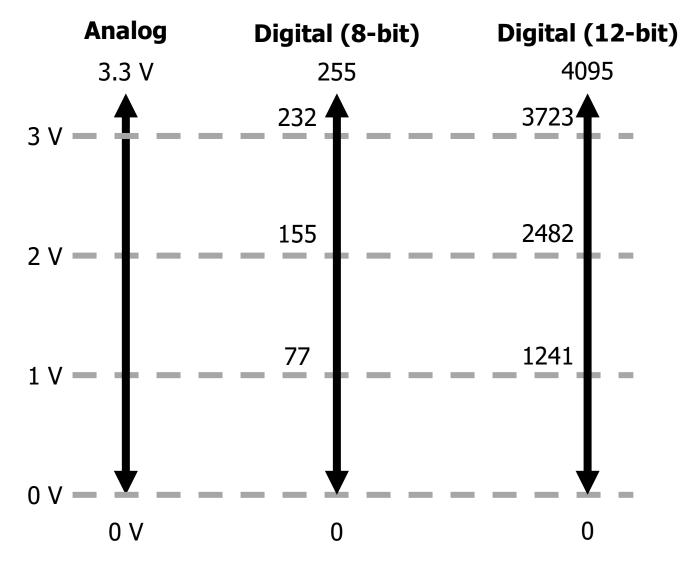


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- Analog voltages are represented by discrete voltage levels
- Comparators are 1-bit ADCs
  - Split into two regions
  - Good ADCs split into 4000-16000 regions
- More levels gives a more accurate representation of the signal

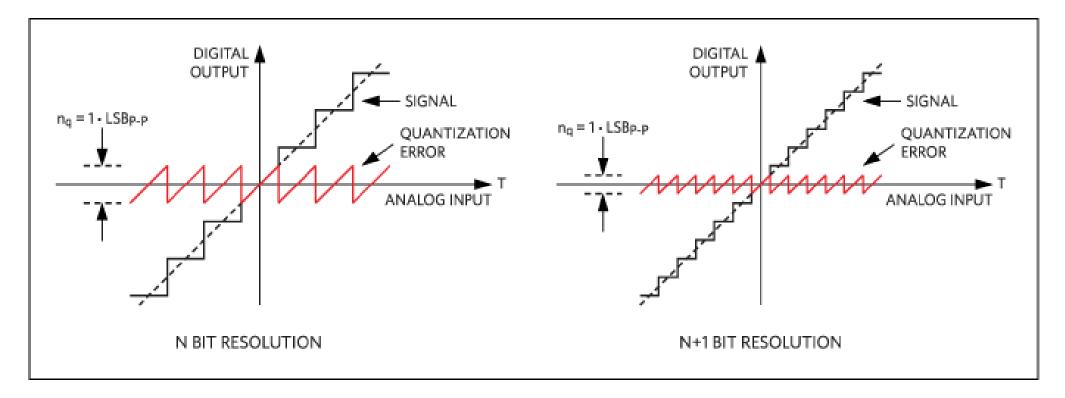
#### Translating voltage and ADC counts



$$Value = \frac{V_{IN}}{V_{REF}} * \left(2^{Resolution} - 1\right)$$

- Ground is usually minimum range
- Resolution depends on hardware
  - Either hardcoded or a selection

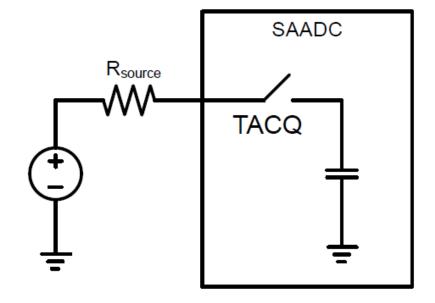
#### Quantization error



- Resolution choice determines magnitude of error
  - Each extra bit halves the magnitude of error

## Analog to digital translation process

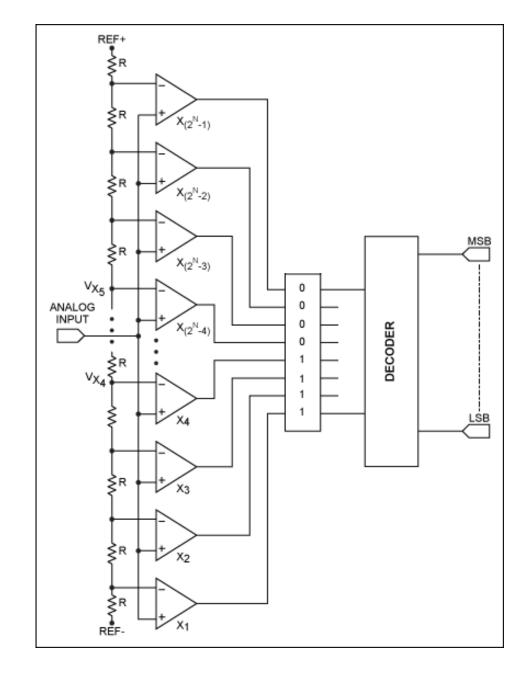
- Two steps:
- 1. Acquisition
  - Read in signal for some amount of time
  - Signal connected to a capacitor
  - Fills capacitor up to voltage level
  - Speed depends on input resistance
    - 1-100 µs is common



- 2. Conversion
  - Determine which digital value the read signal corresponds to

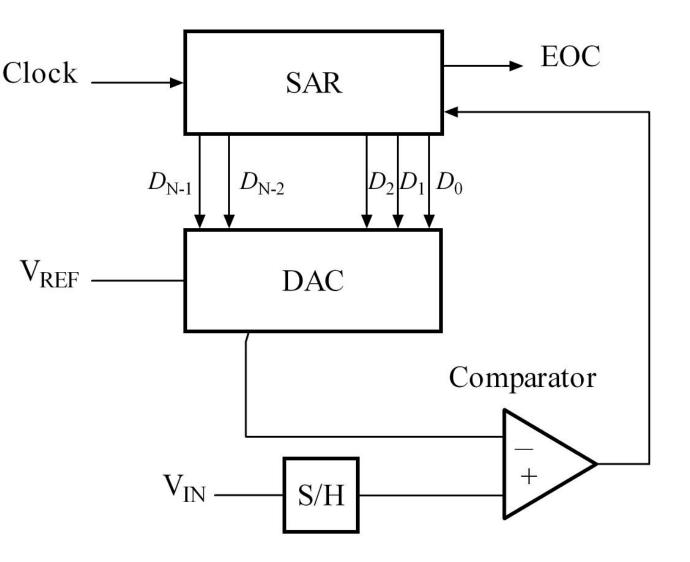
#### Direct-conversion ADC

- Chain comparators together
  - Each with a separate reference voltage
- Digital value determined immediately
  - Also known as "Flash" ADCs
- Downside: needs 2<sup>n</sup>-1 comparators
   Reserved for expensive applications

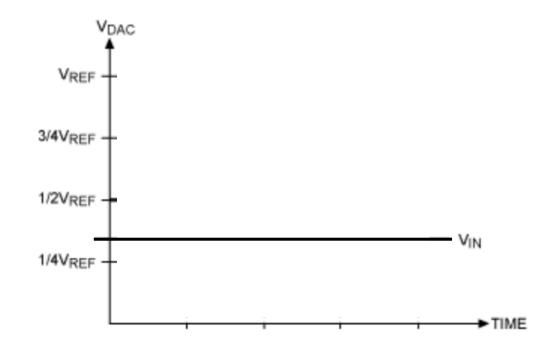


#### Successive-Approximation ADC

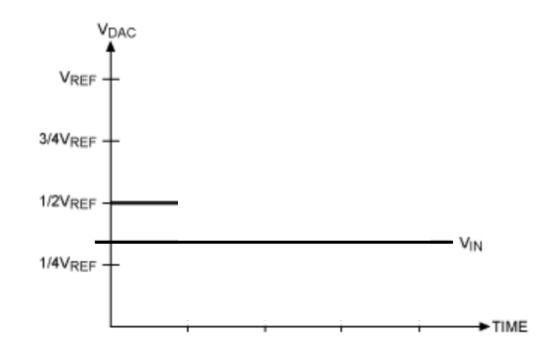
- Method: Binary Search
  - Compare signal to generated reference
  - Increase or decrease reference as needed
  - Repeat
- DAC creates reference (Digital-to-Analog Converter)
  - Final value of DAC is the ADC value



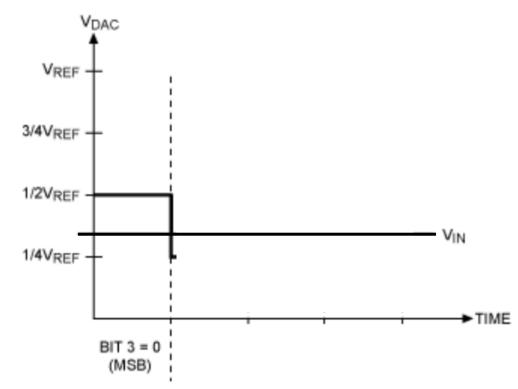
- 4-bit ADC with an input signal  $V_{\rm IN}$ 



- 1. Compare  $\frac{1}{2}$  V<sub>REF</sub> (0b<u>1</u>000) to V<sub>IN</sub>
  - If greater, bit is 1. Else zero

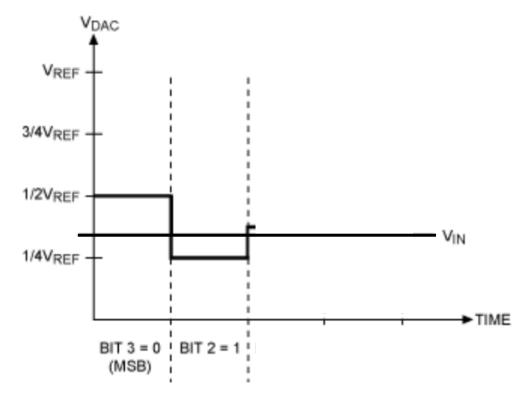


- 1. Compare  $\frac{1}{2}$  V<sub>REF</sub> (0b**0**000) to V<sub>IN</sub>
  - If greater, bit is 1. Else zero
  - +  $V_{\mbox{\scriptsize IN}}$  is less. So set that bit to zero

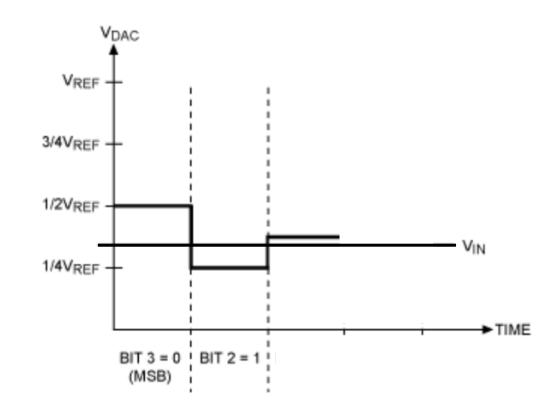


- 2. Compare 1/4 V<sub>REF</sub> (0b0100) to V<sub>IN</sub>
  If greater, bit is 1. Else zero
  - VDAC VREF 3/4V<sub>REF</sub> -1/2V<sub>REF</sub> VIN 1/4V<sub>REF</sub> ►TIME BIT 3 = 0 (MSB)

- 2. Compare 1/4  $V_{REF}$  (0b**01**00) to  $V_{IN}$ 
  - If greater, bit is 1. Else zero
  - $V_{\mbox{\scriptsize IN}}$  is greater. So set that bit to one

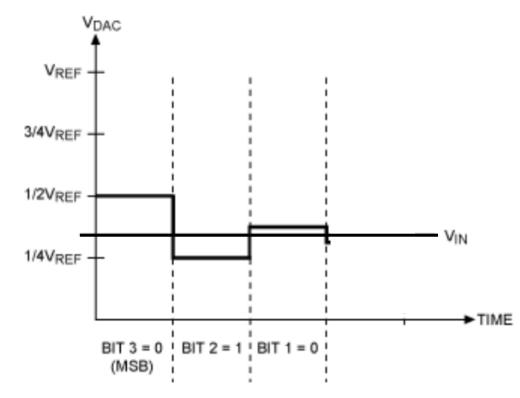


- 3. Compare 3/8  $V_{\text{REF}}$  (0b0110) to  $V_{\text{IN}}$ 
  - If greater, bit is 1. Else zero



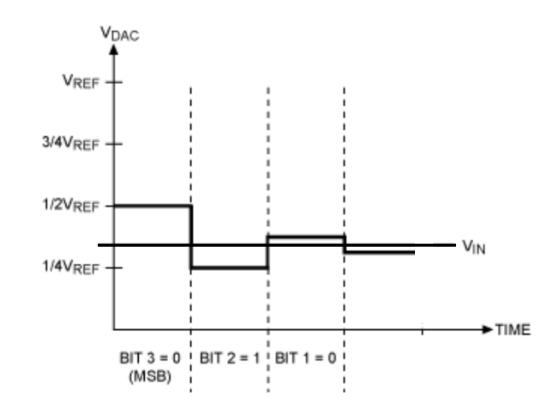
#### 3. Compare 3/8 $V_{REF}$ (0b**010**0) to $V_{IN}$

- If greater, bit is 1. Else zero
- +  $V_{\mbox{\scriptsize IN}}$  is less. So set that bit to zero



#### Successive Approximation Example

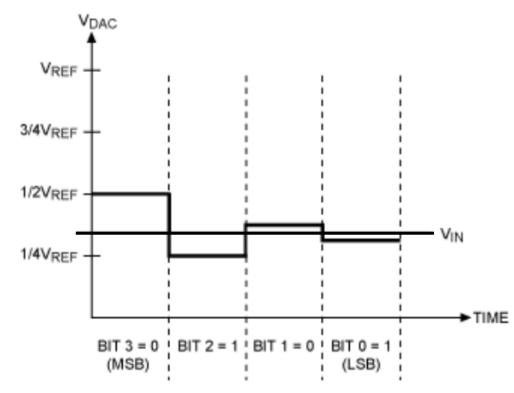
- 4. Compare 5/16  $V_{REF}$  (0b**010**<u>1</u>) to  $V_{IN}$ 
  - If greater, bit is 1. Else zero



## Successive Approximation Example

## 4. Compare 5/16 $V_{\text{REF}}$ (0b**0101**) to $V_{\text{IN}}$

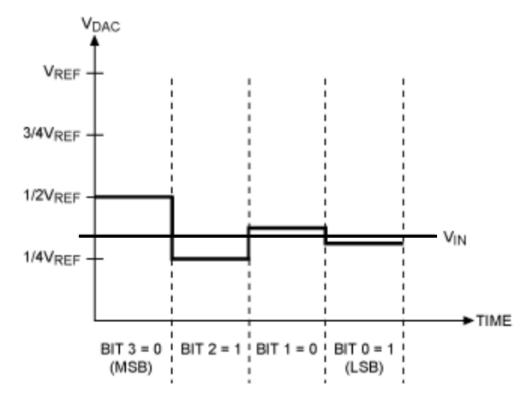
- If greater, bit is 1. Else zero
- +  $V_{\mbox{\scriptsize IN}}$  is greater. So bit is one



## Successive Approximation Example

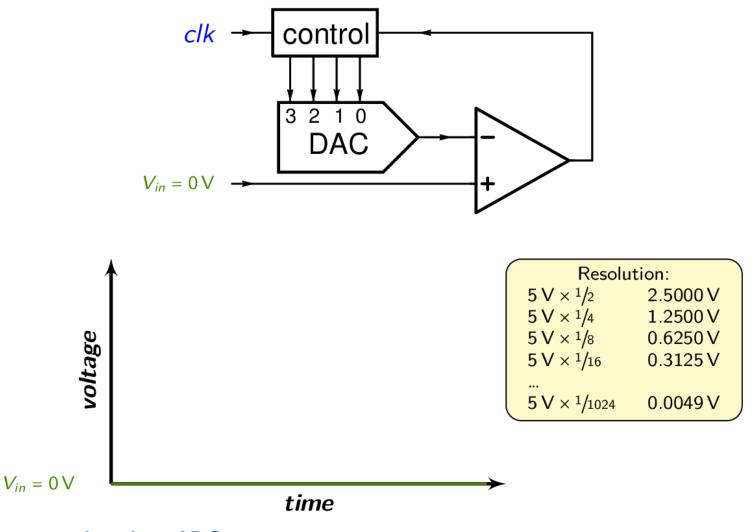
5. Output is 5/16 V<sub>REF</sub> (0b0101)

- Slight underestimate of the real value, but as close as we can get
- More bits would get us even closer



#### Successive Approximation Example

 Performs a binary search to determine correct reference signal value



https://en.wikipedia.org/wiki/Successive-approximation ADC

# Higher resolution ADCs are not free

- Direct-Conversion: more expensive (more silicon)
- SAADC: more time consuming (more binary search time)
- Resolution requirement depends on signal being sensed
  - Temperature sensor probably doesn't need 16-bit ADC
  - Microphone might though!

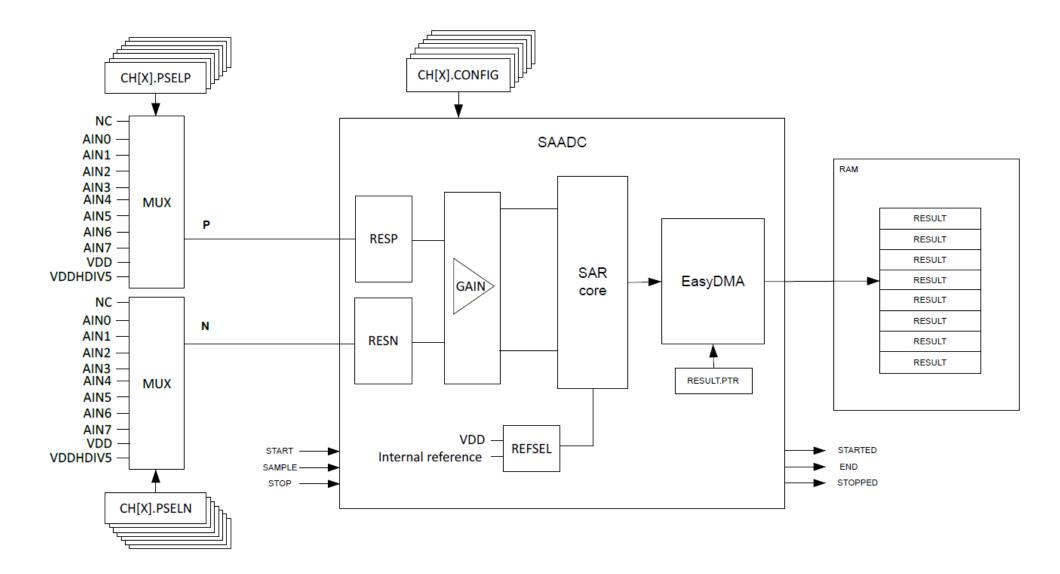
# Outline

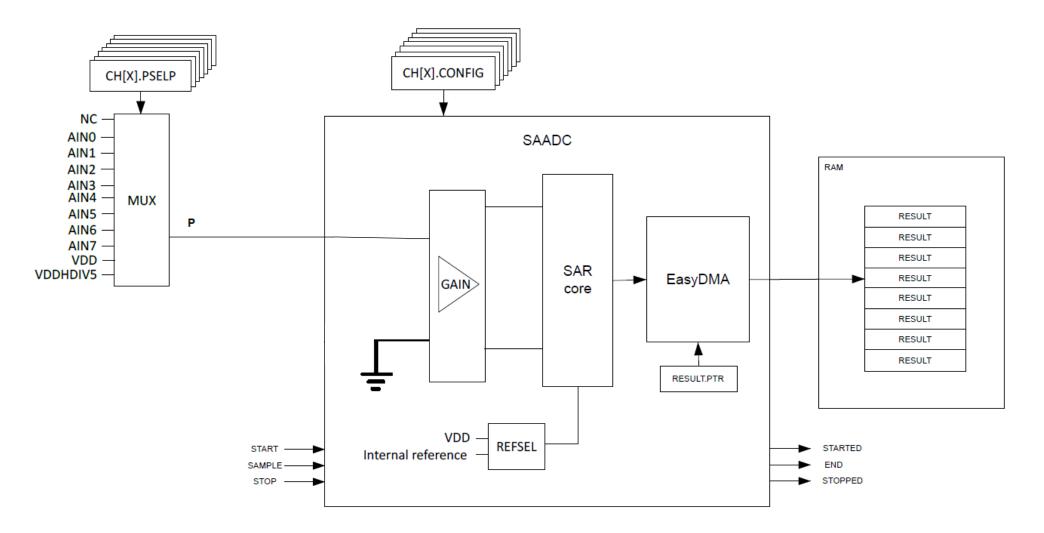
Comparators (and nRF implementations)

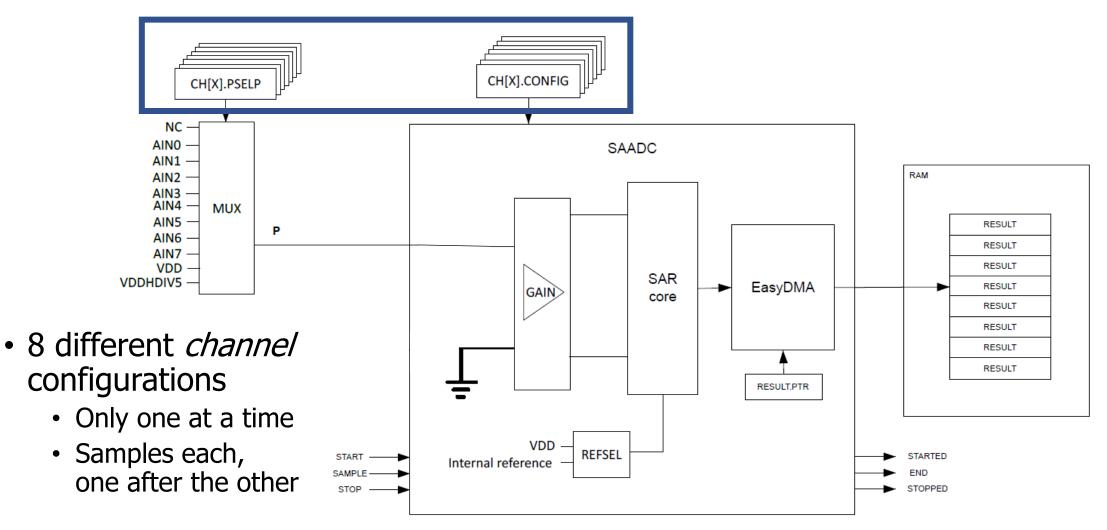
• General ADC Design

nRF ADC Implementation

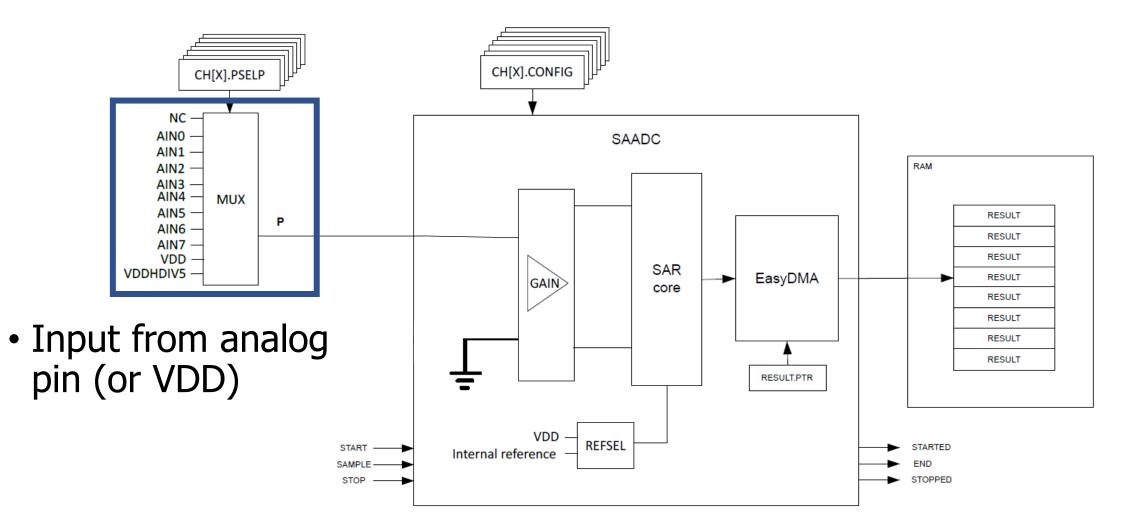
nRF SAADC (Successive Approximation ADC)



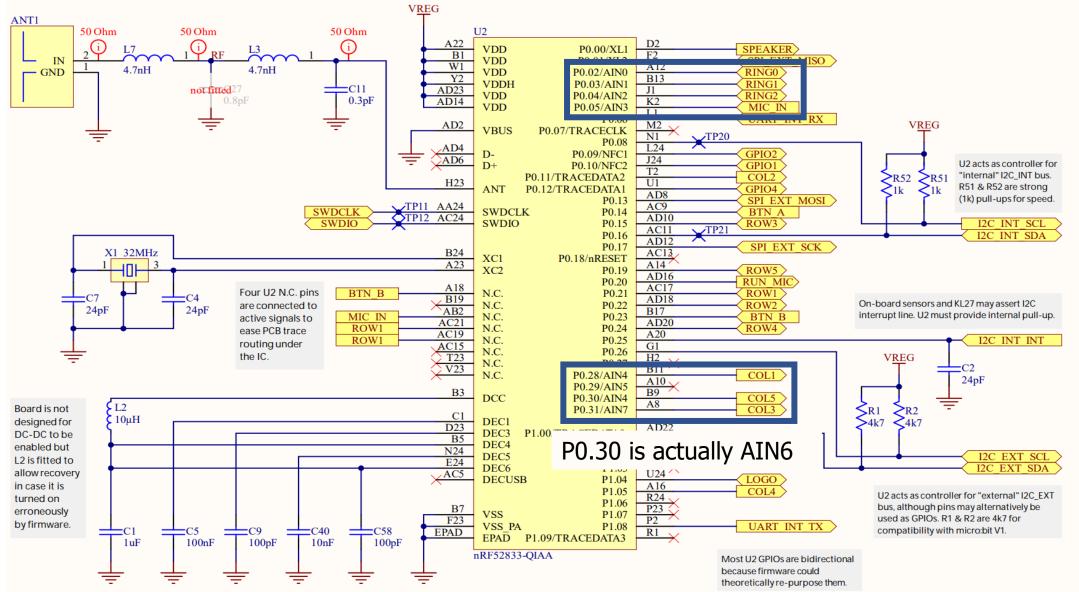


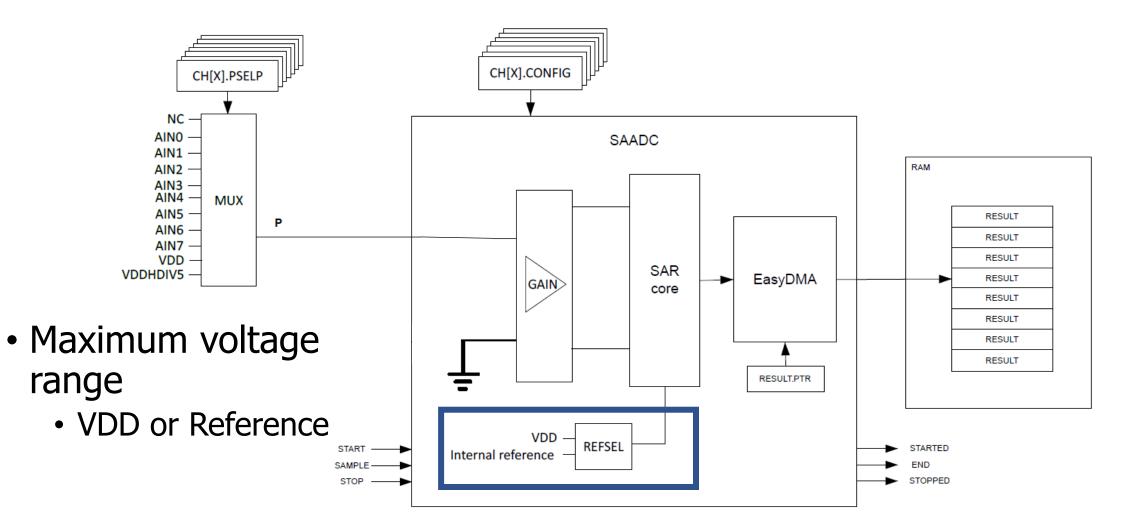


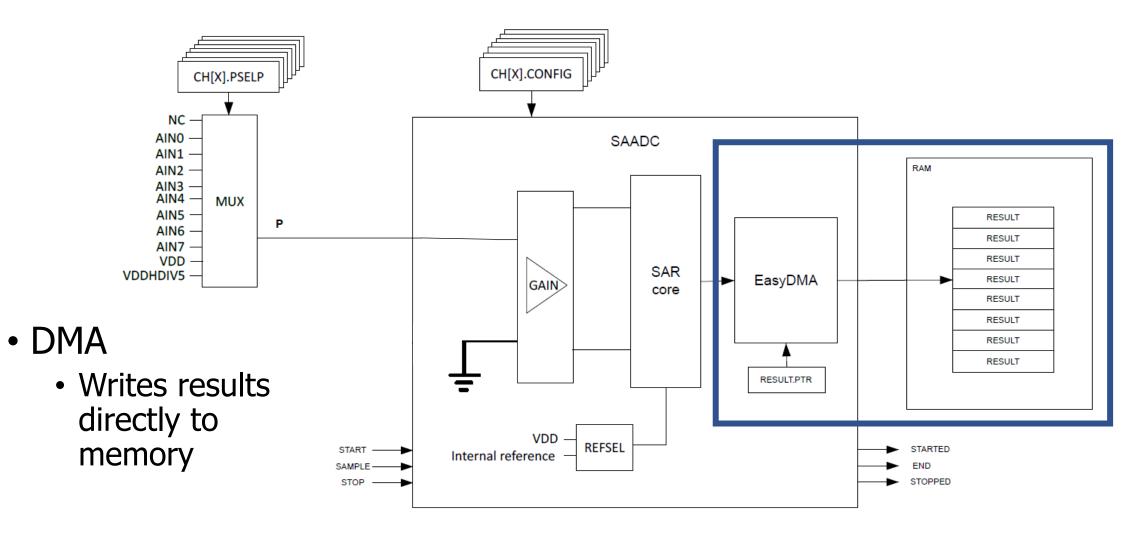
• Essentially virtualization in hardware!



Analog inputs on the Microbit



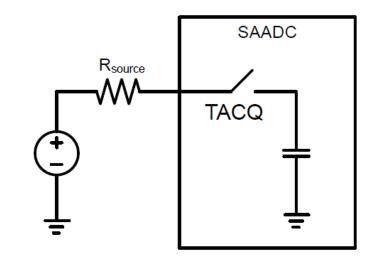




# SAADC Resolution and Sampling

- Resolution is selectable (for the whole peripheral)
  - 8, 10, 12, or 14 bits
  - Result stored as 16-bit value regardless

- Sampling time is selectable (for each channel)
  - 3-40 µs



# Triggering sample collection

- Can be triggered with TASK\_START on demand
  - Including through EVENT->TASK chaining

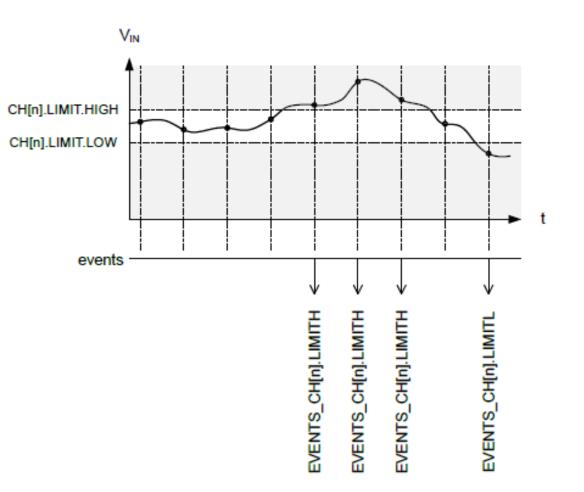
- Includes a timer within itself to automatically trigger sampling
  - Rate = 16 MHz /  $(2^{Scale})$  where scale is 11 bits
  - Maximum rate is 7.8 kHz

# EasyDMA on the SAADC

- There is no register to read ADC results from
- Instead, you must use DMA to collect samples
- At configuration time, provide:
  - Pointer to RAM
    - Must be RAM, not Flash
  - Maximum count of 16-bit samples to be written starting at address
    - Up to 32768
- When complete, a register tells you the amount of samples written to RAM

# Event limit monitoring

- Includes two comparators for each channel
  - High and Low limits
- Generates events whenever transitioning to above High or below Low
  - Events can be ignored if unnecessary



## Temperature sensitivity

- ADCs are often temperature sensitive
  - nRF SAADC: 0.02% per degree C
- Recommends recalibrating every change of 10 degrees C or more
  - Automatic task for calibration
  - Real concern for deployed devices
    - Outdoors
    - Wearable

### Design question

• How many analog samples can the Microbit hold?

#### Design question

- How many analog samples can the Microbit hold?
  - Available: 128 kB RAM, 512 kB Flash (64000 samples in RAM)
  - Questions
    - Are they packed or padded to 16-bit?
    - How much memory are you using for other things?
    - Are you moving them into Flash periodically? (or external storage)

# Outline

Comparators (and nRF implementations)

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